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TABLE OF CONTENTS

PLENARY SESSION

Design- and Manufacturing-aware Test Is Our Future	1
<i>Antun Domic</i>	
Design and Test Challenges for 32 nm and Beyond	2
<i>Shekhar Borkar</i>	

SESSION 1 TEST QUALITY AND DIAGNOSIS

Comparing the Effectiveness of Deterministic Bridge Fault and Multiple-Detect Stuck Fault Patterns for Physical Bridge Defects: A Simulation and Silicon Study	3
<i>Sandeep Kumar Goel, Narendra Devta-Prasanna, Mark Ward</i>	
Defect-Oriented Cell-Aware ATPG and Fault Simulation for Industrial Cell Libraries and Designs	13
<i>F. Hapke, R. Krenz-Baath, A. Glowatz, J. Schloeffel, H. Hashempour, S. Eichenberger, C. Hora, D. Adolfsson</i>	
Test Effectiveness Evaluation Through Analysis of Readily-Available Tester Data	23
<i>Yen-Tzu Lin, R. D. (Shawn) Blanton</i>	
Application of Non-parametric Statistics of the Parametric Response for Defect Diagnosis	33
<i>R. Gudavalli, W. R. Daasch, P. Nigh, D. Heaberlin</i>	

SESSION 2 BOUNDARY-SCAN

Testing Bridges to Nowhere - Combining Boundary Scan and Capacitive Sensing	43
<i>Stephen Sunter, Kenneth P. Parker</i>	
Intel®IBIST, the Full Vision Realized	53
<i>Jay Nejedlo, Rahul Khanna</i>	
Fast Extended Test Access Via JTAG and FPGAs	64
<i>Sergei Devadze, Artur Jutman, Igor Aleksejev, Raimund Ubar</i>	
Boundary-Scan Adoption – An Industry Snapshot with Emphasis on the Semiconductor Industry	71
<i>Philip B. Geiger, Steve Butkovich</i>	

SESSION 4 DELAY TEST AND POWER-AWARE TEST

Minimizing Outlier Delay Test Cost in the Presence of Systematic Variability	81
<i>Dragoljub (Gagi) Drmanac, Brendon Bolin, Li C. Wang, Magdy S. Abadir</i>	
Accurate Measurement of Small Delay Defect Coverage of Test Patterns	91
<i>Narendra Devta-Prasanna, Sandeep Kumar Goel, Arun Gunda, Mark Ward, Prabhakaran Krishnamurthy</i>	
Capture Power Reduction Using Clock Gating Aware Test Generation	101
<i>Krishna Chakravadhanula, Vivek Chickermane, Brion Keller, Patrick Gallagher, Prashant Narang</i>	

SESSION 5 UNDERSTANDING FREQUENCY BEHAVIOR ON A DEVICE

AutoRex: An Automated Post-Silicon Clock Tuning Tool	110
<i>D. Tadesse, J. Grodstein, R. I. Bahar</i>	
Using Transition Test to Understand Timing Behavior of Logic Circuits on UltraSPARC™ T2 Family	120
<i>Liang-Chi Chen, Paul Dickinson, Peter Dahlgren, Scott Davidson, Olivier Caty, Kevin Wu</i>	
Data Learning Techniques and Methodology for Fmax Prediction	130
<i>Janine Chen, Li C. Wang, Po-Hsien Chang, Jing Zeng, Stanley Yu, Michael Mateja</i>	

SESSION 6 RF TESTING

Built-in EVM Measurement for OFDM Transceivers Using All-digital DFT	140
<i>Ender Yilmaz, Afsaneh Nassery, Sule Ozev, Erkan Acar</i>	

Enabling GSM/GPRS/EDGE EVM Testing on Low Cost Multi-Site Testers	150
<i>Bobby Lai, Chris Rivera, Khurram Waheed</i>	
Low Cost AM/AM and AM/PM Distortion Measurement Using Distortion-to-Amplitude Transformations	157
<i>Shreyas Sen, Shyam Devarakond, Abhijit Chatterjee</i>	

SESSION 7 EMBEDDED MEMORY TEST AND REPAIR

Fault Diagnosis for Embedded Read-Only Memories	167
<i>N. Mukherjee, A. Pogiel, J. Rajski, J. Tyszer</i>	
A Novel Test Flow for One-Time-Programming Applications of NROM Technology	177
<i>Ching-Yu Chin, Yao-Te Tsou, Chi-Min Chang, Mango C. T. Chao</i>	
A Comprehensive TCAM Test Scheme: An Optimized Test Algorithm Considering Physical Layout and Combining Scan Test with At-Speed BIST Design	186
<i>Hsiang-Huang Wu, Jih-Nung Lee, Ming-Cheng Chiang, Po-Wei Liu, Chi-Feng Wu</i>	

SESSION 8 MICROPROCESSOR SUPPLY NOISE AND I/O TEST

On-Chip Power Supply Noise Measurement Using Time Resolved Emission (TRE) Waveforms of Light Emission from Off-State Leakage Current (LEOSLC)	196
<i>Franco Stellari, Peilin Song, John Sylvestri, Darrell Miles, Orazio Forlenza, Donato Forlenza</i>	
Voltage Transient Detection and Induction for Debug and Test	206
<i>Rex Petersen, Pankaj Pant, Pablo Lopez, Aaron Barton, Jim Ignowski, Doug Josephson</i>	
Cache-Resident Self-Testing for I/O Circuitry	216
<i>Sankar Gurumurthy, Darren Bertanzetti, Peter Jakobsen, Jeff Rearick</i>	

SESSION 9 ADVANCES IN TEST COMPRESSION

Compression-Aware Pseudo-Functional Testing	224
<i>Feng Yuan, Qiang Xu</i>	
Compression Based on Deterministic Vector Clustering of Incompatible Test Cubes	234
<i>G. Mrugalski, N. Mukherjee, J. Rajski, D. Czysz, J. Tyszer</i>	
On Simultaneous Shift- and Capture-Power Reduction in Linear Decompressor-Based Test Compression Environment	244
<i>Xiao Liu, Qiang Xu</i>	

SESSION 10 LIMITED-ACCESS IN-CIRCUIT BOARD TEST TECHNIQUES

An Economical, Precise and Limited Access In-Circuit Test Method for Pulse-Width Modulation (PWM) Circuits	254
<i>Albert Yeh, Jesse Chou, Max Lin</i>	
Augmenting Board Test Coverage with New Intel Powered Opens Boundary Scan Instruction	263
<i>Chwee Liong Tee, Tzyy Haw Tan, Chin Chuan Ng</i>	
An Outlier Detection Based Approach for PCB Testing	273
<i>Xin He, Yashwant Malaiya, Anura P. Jayasumana, Kenneth P. Parker, Stephen Hird</i>	

SESSION 11 JITTER, JITTER, JITTER!

SSC Applied Serial ATA Signal Generation and Analysis By Analog Tester Resources	283
<i>Hideo Okawara</i>	
A Robust Method for Identifying a Deterministic Jitter Model in a Total Jitter Distribution	292
<i>Takahiro J. Yamaguchi, Kiyotaka Ichiyama, Harry X. Hou, Masahiro Ishida</i>	
Dynamic Arbitrary Jitter Injection Method For >6.5Gb/s SerDes Testing	302
<i>T. Fujibe, M. Suda, K. Yamamoto, Y. Nagata, K. Fujita, D. Watanabe, T. Okayasu</i>	
A Timestamping Method Using Reduced Cost ADC Hardware	312
<i>Timothy D. Lyons</i>	

SESSION 12 TEST POTPOURRI

A Novel Architecture for On-Chip Path Delay Measurement	320
<i>Xiaoxiao Wang, Mohammad Tehranipoor, Ramyanshu Datta</i>	
Low Cost Test Point Insertion Without Using Extra Registers for High Performance Design	330
<i>Haoxing Ren, Mary Kusko, Victor Kravets, Rona Yaari</i>	
Test Economics for Homogeneous Manycore Systems	338
<i>Lin Huang, Qiang Xu</i>	
Physical Defect Modeling for Fault Insertion in System Reliability Test	348
<i>Zhaobo Zhang, Zhanglei Wang, Xinli Gu, Krishnendu Chakrabarty</i>	

SESSION 13 TEST TECHNIQUES FOR ADCS/MIXED-SIGNAL DEVICES

BIST Scheme for RF VCOs Allowing the Self-Correction of the CUT	358
<i>L. Testa, H. Lapuyade, Y. Deval, O. Mazouffre, J. L. Carbonero, J. B. Begueret</i>	
A2DTest: A Complete Integrated Solution for On-chip ADC Self-test and Analysis	368
<i>Brendan Mullane, Vincent O'Brien, Ciaran Macnamee, Thomas Fleischmann</i>	
New Modeling Methods for Bounded Gaussian Jitter (BGJ)/Noise (BGN) and Their Applications in Jitter/Noise Estimation/Testing	378
<i>Masashi Shimanouchi, Mike Peng Li, Daniel Chow</i>	

SESSION 14 IMPROVING YIELD ON YOUR SAME OLD ATE

Thermal Characterization of BIST, Scan Design and Sequential Test Methodologies	386
<i>Muzaffer O. Simsir, Niraj K. Jha</i>	
Cost-Effective Approach to Improve EMI Yield Loss	395
<i>Hsuan-Chung Ko, Deng-Yao Chang, Cheng-Nan Hu</i>	
A Development Platform and Electronic Modules for Automated Test up to 20 Gbps	403
<i>D. C. Keezer, C. Gray, A. Majid, D. Minier, P. Ducharme</i>	

SESSION 15 GETTING WORKING SILICON

Microprocessor System Failures Debug and Fault Isolation Methodology	414
<i>M. Enamul Amyeen, Srikanth Venkataraman, Mun Wai Mak</i>	
Design for Failure Analysis Inserting Replacement-type Observation Points for LVP	424
<i>Junpei Nonaka, Toshio Ishiyama, Kazuki Shigeta</i>	
Feature Based Similarity Search with Application to Speedpath Analysis	434
<i>Nicholas Callegari, Li C. Wang, Pouria Bastani</i>	

SESSION 16 VERIFICATION AND DIAGNOSTIC ATPG

Speeding Up Bounded Sequential Equivalence Checking with Cross-Timeframe State-Pair Constraints from Data Learning	444
<i>Chia-Ling(Lynn) Chang, Charles H. P. Wen, Jayanta Bhadra</i>	
An Ant Colony Optimization Technique for Abstraction-Guided State Justification	452
<i>Min Li, Michael S. Hsiao</i>	
Diagnostic Test Generation for Transition Faults Using a Stuck-at ATPG Tool	462
<i>Yoshinobu Higami, Yosuke Kurose, Satoshi Ohno, Hironori Yamaoka, Hiroshi Takahashi, Yoshihiro Shimizu, Takashi Aikyo, Yuzo Takamatsu</i>	

SESSION 17 X-HANDLING FOR MISR SIGNATURE

X-Alignment Techniques for Improving the Observability of Response Compactors	471
<i>Ozgur Sinanoglu, Sobeeh Almkhaizim</i>	
An Industrial Case Study for X-Canceling MISR	481
<i>Joon-Sung Yang, Nur A. Touba, Shih-Yu Yang, T. M. Mak</i>	
Test Point Insertion Using Functional Flip-Flops to Drive Control Points	491
<i>Joon-Sung Yang, Benoit Nadeau-Dostie, Nur A. Touba</i>	

SESSION 18 INNOVATIVE SOLUTIONS

Running Scan Test on Three Pins: Yes We Can! 501
Jocelyn Moreau, Thomas Droniou, Philippe Lebourg, Paul Armagnat

A Novel Array-based Test Methodology for Local Process Variation Monitoring 511
Tseng-Chin Luo, Mango C. T. Chao, Michael S. Y. Wu, Kuo-Tsai Li, Chin. C. Hsia, Huan-Chi Tseng, Chuen-Uan Huang, Yuan-Yao Chang, Samuel C. Pan, Konrad K. L. Young

Fast Circuit Topology Based Method to Configure the Scan Chains in Illinois Scan Architecture..... 520
Swapneel Donglikar, Mainak Banga, Maheshwar Chandrasekar, Michael S. Hsiao

LECTURE 1 POST-SILICON TEST, DEBUG AND VALIDATION

Structural Test of Power-Only Defects: ATPG or Ad-hoc? 530
Baosheng Wang, Grady Giles, Jayalakshmi Rajaraman, Kanwaldeep Sobti, Derrick Losli, Dwight Elvey, Jeff Fitzgerald, Ron Walther, Jeff Rearick

Using the Multiple-Clue Approach for System Testing on AIRBUS FAL (Final Assembly Line)..... 531
Fassely Doumbia, Odile Laurent, Didier Atger, Chantal Robach

Post-Silicon Validation: It's the Unique Fails that Hurt You..... 540
P. K. Ahuja

LECTURE 3 INNOVATIVE APPROACHES TO PERFORMANCE TEST

Tolerance of Performance Degrading Faults for Effective Yield Improvement..... 541
Tong-Yu Hsieh, Melvin A. Breuer, Murali Annaram, Sandeep K. Gupta, Kuen-Jong Lee

The Best of Both Worlds: Merging the Benefits of Rack & Stack and Universal ATE 551
Ping Lu, Daniel Glaser, Gürkan Uygur, Klaus Helmreich

At-speed Test on the QorIQ™ P2020 Platform..... 561
Colin D. Renfrew, Brian Booth, Shweta Latawa, Rick Woltenberg, Carol Pyron

EMBEDDED TUTORIAL 1 TESTING 3-D CHIPS CONTAINING THROUGH-SILICON VIAS

Testing 3D Chips Containing Through-Silicon Vias..... 569
Erik Jan Marinissen, Yervant Zorian

EMBEDDED TUTORIAL 3 NEW BOUNDARY-SCAN-BASED STANDARDS

Doing More with Less – An IEEE 1149.7 Embedded Tutorial : Standard for Reduced-pin and Enhanced-functionality Test Access Port and Boundary-Scan Architecture 580
Adam W Ley

PANEL 1 40 YEARS OF RELIABLE COMPUTING AT STANFORD CRC

40 Years of Reliable Computing at Stanford CRC 590
Nur A. Touba

The ROAR Project (1997-2002)— Looking Back 591
Nirmal R. Saxena

The ARGOS Project..... 592
Na

Test Chip Experiments at Stanford CRC 593
Ahmed Al-Yamani, Jonathan Chang, Piero Franco, James Li, Siyad Ma, Subhasish Mitra, Intaik Park, Chao-Wen Tseng, Erik Volkerink

PANEL 2 CAN EDA HELP SOLVE ANALOG TEST AND DFT CHALLENGES?

Can EDA Help Solve Analog Test and DFT Challenges?..... 594
R. Datta

EDA for Analog DFT? – Designers Must Get on the Bus	595
<i>Stephen Sunter</i>	

PANEL 3 TESTING OF 3-D CHIPS: IS THERE ANYTHING NEW UNDER THE SUN?

Testing of 3D Chips: Is There Anything New Under the Sun?	596
<i>E. J. Marinissen</i>	
Test Challenges for 3D-SICs: All the Old, Most of the Recent, and Then Some New!	597
<i>Erik Jan Marinissen</i>	
Implications of 3-D Integrated Circuits at Board Test	598
<i>Kenneth P. Parker</i>	

PANEL 4 POWER FAULTS – WHAT IS OUR TOLERANCE FOR DEFECTS?

Power Faults - What is Our Tolerance for Defects?	600
<i>Grady Giles</i>	

PANEL 5 PHYSICALLY-AWARE DFT: IS IT WORTH ALL THE HEAVY LIFTING?

Physically Aware DFT: Is It Worth All The Heavy Lifting?	601
<i>Leroy Winenberg</i>	

PANEL 6 PREDICTIVE SOLUTIONS FOR TEST – THE NEXT DFT PARADIGM?

Predictive Solutions for Test – The Next DFT Paradigm?	603
<i>Chris Allsup, Rohit Kapur</i>	

PANEL 7 HOW (UN)AFFORDABLE IS THE TRUE COST OF TEST?

Panel Synopsis - How (Un)Affordable is True Cost of Test?	604
<i>Rubin A. Parekhji</i>	
Panel Synopsis - How (Un)Affordable is True Cost of Test?	606
<i>Alfred Crouch</i>	
How (Un)Affordable is the True Cost of Test?	607
<i>Scott Davidson</i>	

POSTER SESSION

Eliminating Product Infant Mortality Failures Using Prognostic Analysis	608
<i>Len Losik</i>	
Automatic Diagnostic Tool for Analog-Mixed Signal and RF Load Boards	609
<i>Sukeshwar Kannan, Bruce C. Kim</i>	
Scalable and Efficient Integrated Test Architecture	610
<i>Michele Portolan, Suresh Goyal, Bradford Van Treuren</i>	
Very-Low-Voltage Testing of Amorphous Silicon TFT Circuits	611
<i>Shiue-Tsung Shen, Wei-Hsiao Liu, James Chien-Mo Li, I-Chun Cheng</i>	
Low Power Multi-Chains Encoding Scheme for SoC in Low-Cost Environment	612
<i>Po-Han Wu, Jiann-Chyi Rau</i>	
Power and Thermal Constrained Test Scheduling	613
<i>Chunhua Yao, Kewal K. Saluja, Parameswaran Ramanathan</i>	
Power Scan: DFT for Power Switches in VLSI Designs	614
<i>Bing-Chuan Bai, Chien-Mo Li, Augusli Kifli, Even Tsai, Kun-Cheng Wu</i>	
IEEE P1687 IJTAG : A Presentation of Current Technology	615
<i>Ken Posse, Al Crouch, Jeff Rearick</i>	
Test Mode Entry and Exit Methods for IEEE P1581 Compliant Devices	616
<i>Heiko Ehrenberg</i>	

A Novel Multisite Testing Techniques by Using Frequency Synthesizer	617
<i>Boyon Kim, Il-Chan Park, Giseob Song, Wooseong Choi, Byeong-Yun Kim, Kyutaek Lee, Chi-Young Choi</i>	
Design-for-Secure-Test for Crypto Cores	618
<i>Youhua Shi, Nozomu Togawa, Masao Yanagisawa, Tatsuo Ohtsuki</i>	
Non-Invasive RF Built-in Testing Using On-chip Temperature Sensors	619
<i>E. Aldrete, M. Onabajo, J. Altet, D. Mateo, J. Silva-Martinez</i>	
NAND Flash Testing: A Preliminary Study on Actual Defects	620
<i>P. D. Mauroux, A. Virazel, A. Bosio, L. Dilillo, P. Girard, S. Pravossoudovitch, B. Godard</i>	
Built-in Self Test for Error Vector Magnitude Measurement of RF Transceiver	621
<i>Bilal El Kassir, Christophe Kelma, Bernard Jarry, Michel Campovecchio</i>	
Fine Resolution Double Edge Clipping with Calibration Technique for Built-In At-Speed Delay Testing	622
<i>Chen-I Chung, Shuo-Wen Chang, Ching-Hwa Cheng</i>	
Portable Simulation/Emulation Stimulus on an Industrial-strength SoC	623
<i>Francisco Torres, Rohit Srivastava, Javier Ruiz, H. P. Wen, Mrinal Bose, Jayanta Bhadra</i>	
Test Infrastructures Evaluation at Transaction Level	624
<i>Stefano Di Carlo, Nadereh Hatami, Paolo Prinetto</i>	
Trace Signal Selection for Debugging Electrical Errors in Post-Silicon Validation	625
<i>Xiao Liu, Qiang Xu</i>	
Defect Coverage of Non-intrusive Board Tests (NBT): What Does it Mean When a Non-intrusive Board Test Passes?	626
<i>Adam W. Ley</i>	
What is IEEE P1149.8.1 and Why?	627
<i>Ken Parker, Jeff Burgess</i>	
Manufacturing Data: Maximizing Value Using Component-To-System Analysis	628
<i>Matthias Kamm</i>	
High Speed I/O Test Cable Assembly Interfaces for Next Generation Multi-Gigabit Serial Protocols	629
<i>Jim Vana, Alexander Barr, Richard Scherer, Abhay Joshi</i>	

ITC 2008 BEST PAPER

Test Access Mechanism for Multiple Identical Cores	630
<i>Grady Giles, Jing Wang, Anuja Sehgal, Kedarnath J. Balakrishnan, James Wingfield</i>	
Author Index	